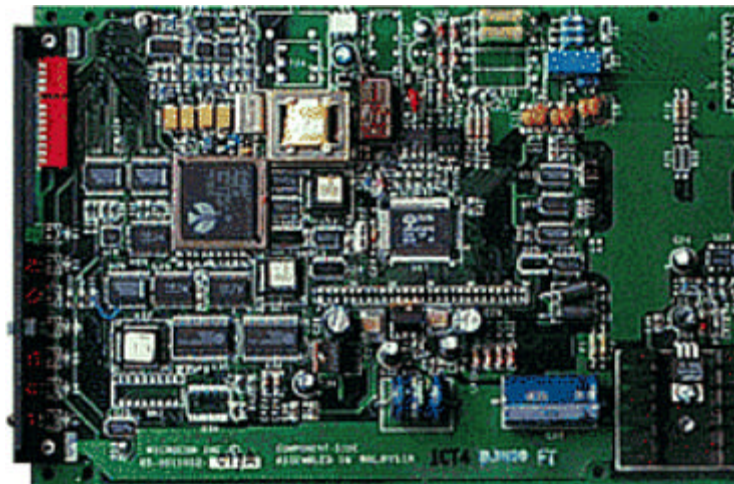




Electromagnetic Interference Susceptibility Characterization of New Technology

E1



Objective

An automated test system with associated processes has been developed that demonstrates the capability of selected high priority semiconductor devices. Special test techniques are being developed to consider the different types of integrated circuits, operating conditions to which IC's may be subjected. The tests will be meaningful, repeatable, and permanent documentation of each test will be provided.

Why Needed

An electromagnetic interference (EMI) susceptibility characterization has been developed to update existing information developed on the older and slower electronic devices. New technology devices of interest include integrated circuits (IC's), Electro-optical, and electrical/electronic sensors.

Point of Contact

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Sponsor

NASA Space Environments and Effects (SEE) Program